

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY			
V_{DS} (V)	$R_{DS(on)}$ (Ω)	I_D (A) ^f	Q_g (Typ.)
40	0.0075 at $V_{GS} = 10$ V	58	21 nC
	0.009 at $V_{GS} = 4.5$ V	53	

FEATURES

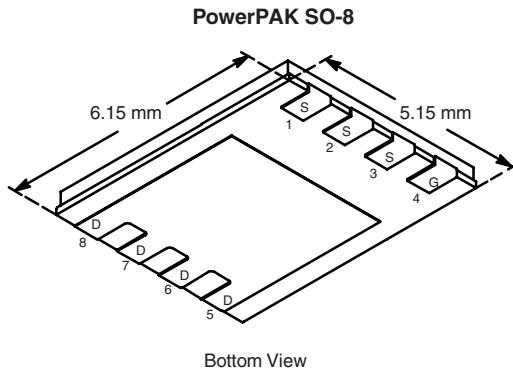
- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested



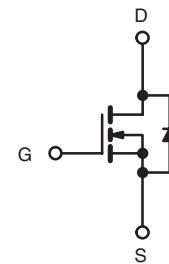
RoHS
COMPLIANT

APPLICATIONS

- Synchronous Rectifier



Bottom View



Ordering Information: Si7884BDP-T1-E3 (Lead (Pb)-free)

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	40	V	
Gate-Source Voltage	V_{GS}	± 20		
Continuous Drain Current ($T_J = 150$ °C)	I_D	58 ^f	A	
		46 ^f		
		18.5 ^{a, b}		
		14.8 ^{a, b}		
Pulsed Drain Current	I_{DM}	50	mJ	
Avalanche Current	I_{AS}	33		
Avalanche Energy	E_{AS}	54		
Continuous Source-Drain Diode Current	I_S	38 ^f		
		3.8 ^{a, b}		
Maximum Power Dissipation	P_D	46	W	
		29		
		4.6 ^{a, b}		
		3.0 ^{a, b}		
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{c, d}		260		

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, e}	$t \leq 10$ s	R_{thJA}	22	27
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	2.2	2.7 °C/W

Notes:

- Surface Mounted on 1" x 1" FR4 board.
- $t = 10$ s.
- See Solder Profile (<http://www.vishay.com/ppg?73257>). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- Maximum under Steady State conditions is 70 °C/W.
- Calculation based on maximum allowable junction temperature. Package limitation current is 32 A.

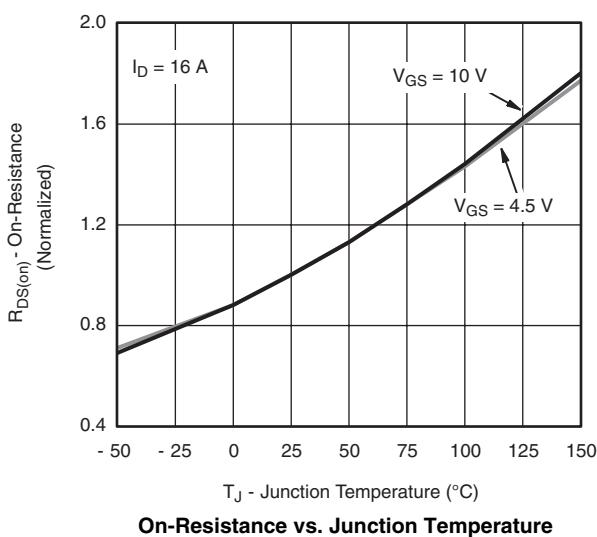
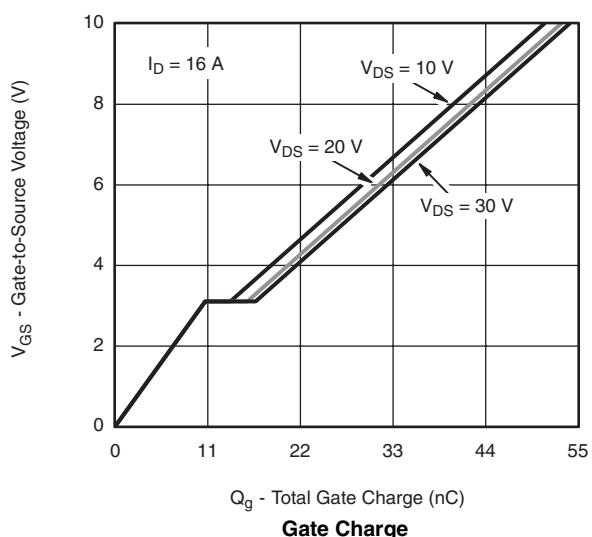
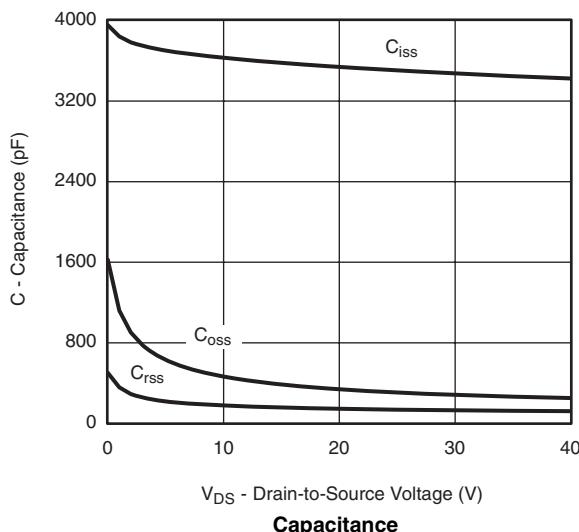
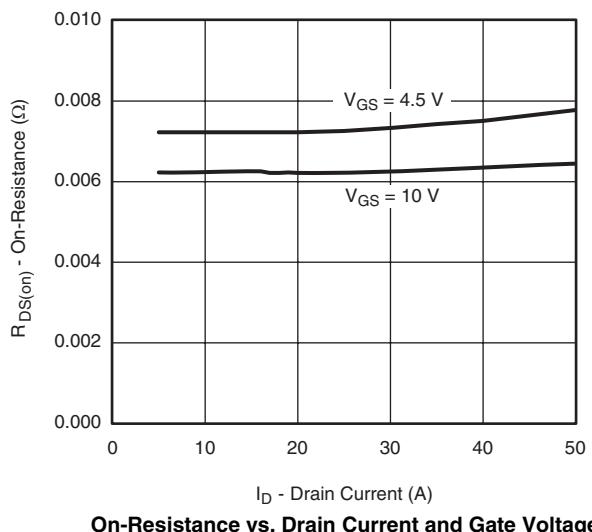
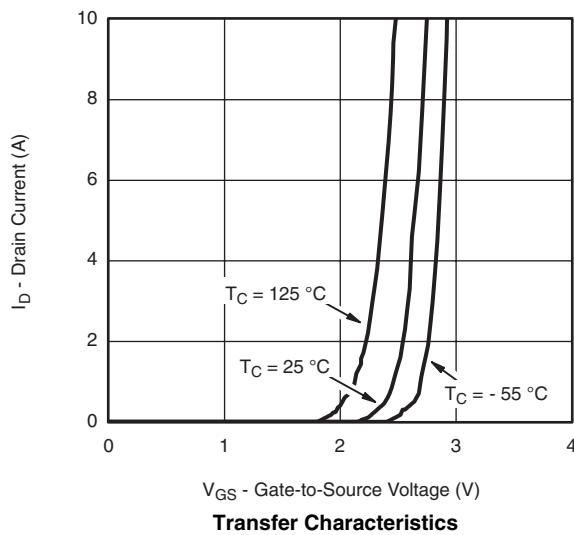
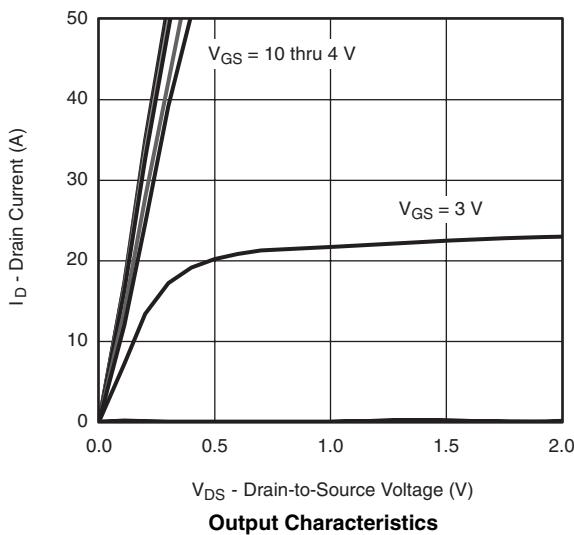
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

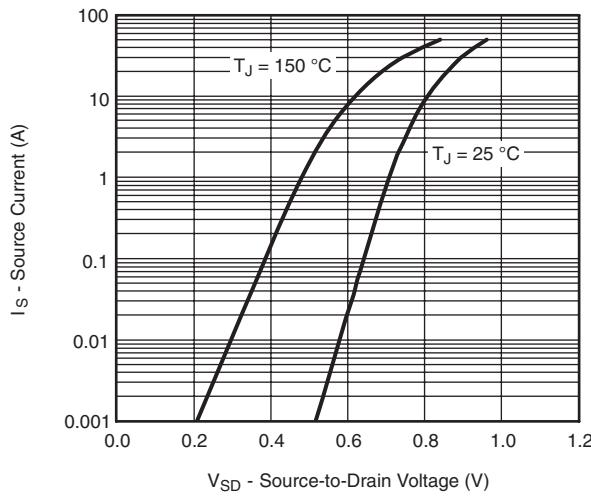
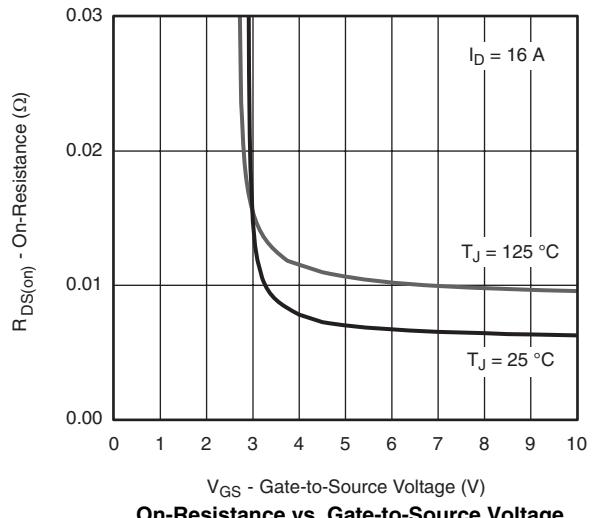
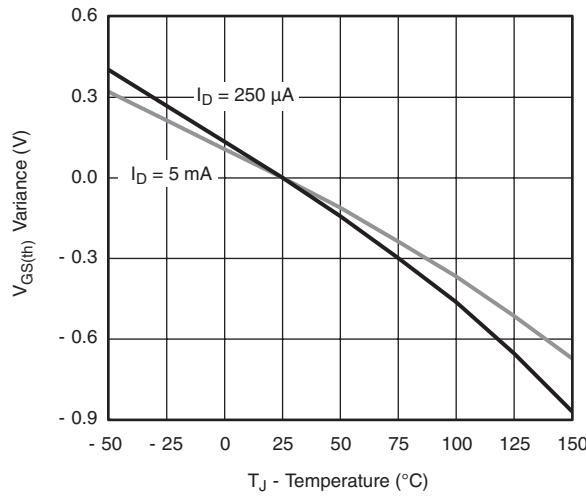
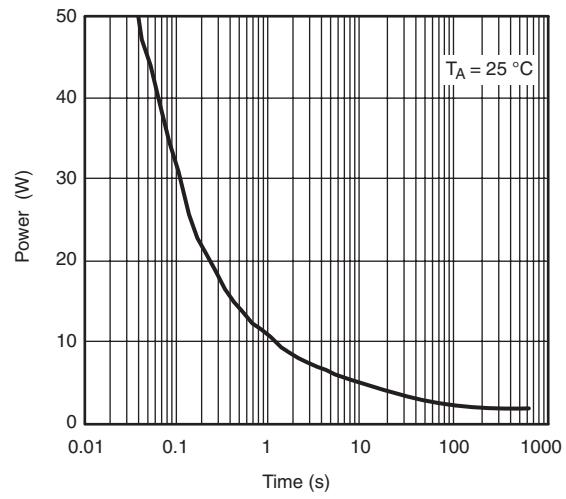
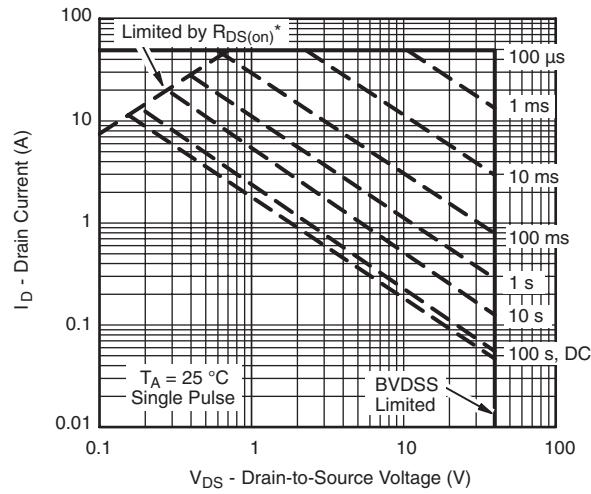
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		46		$\text{mV}/^\circ\text{C}$
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 6.7		
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1		3	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			5	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			A
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 16 \text{ A}$		0.0062	0.0075	Ω
		$V_{GS} = 4.5 \text{ V}, I_D = 14 \text{ A}$		0.0073	0.009	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 16 \text{ A}$		55		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		3540		pF
Output Capacitance	C_{oss}			335		
Reverse Transfer Capacitance	C_{rss}			142		
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 16 \text{ A}$		51	77	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 16 \text{ A}$		21	32	
Gate-Drain Charge	Q_{gd}			10.7		
Gate Resistance	R_g	$f = 1 \text{ MHz}$		3.0		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 20 \text{ V}, R_L = 2 \Omega$ $I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		0.75	1.5	Ω
Rise Time	t_r			30	45	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			14	21	
Fall Time	t_f			38	60	
Turn-On Delay Time	$t_{d(\text{on})}$			11	17	
Rise Time	t_r			14	21	
Turn-Off Delay Time	$t_{d(\text{off})}$			10	15	
Fall Time	t_f			32	50	
				8	15	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			32	A
Pulse Diode Forward Current	I_{SM}				50	
Body Diode Voltage	V_{SD}	$I_S = 10 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 10 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		25	50	ns
Body Diode Reverse Recovery Charge	Q_{rr}			19	38	nC
Reverse Recovery Fall Time	t_a			13		ns
Reverse Recovery Rise Time	t_b			12		

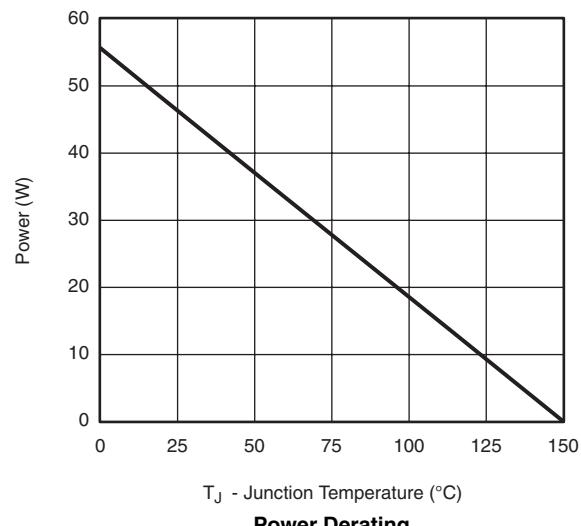
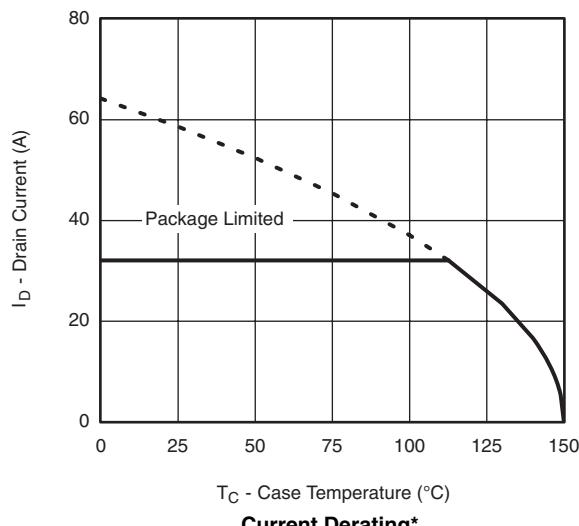
Notes:

- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

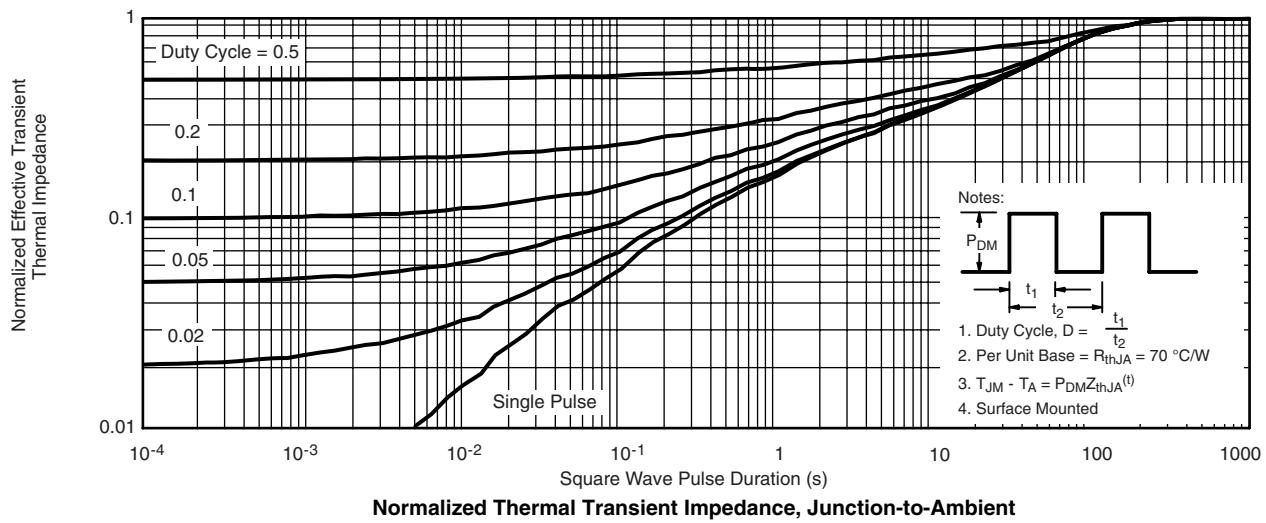
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


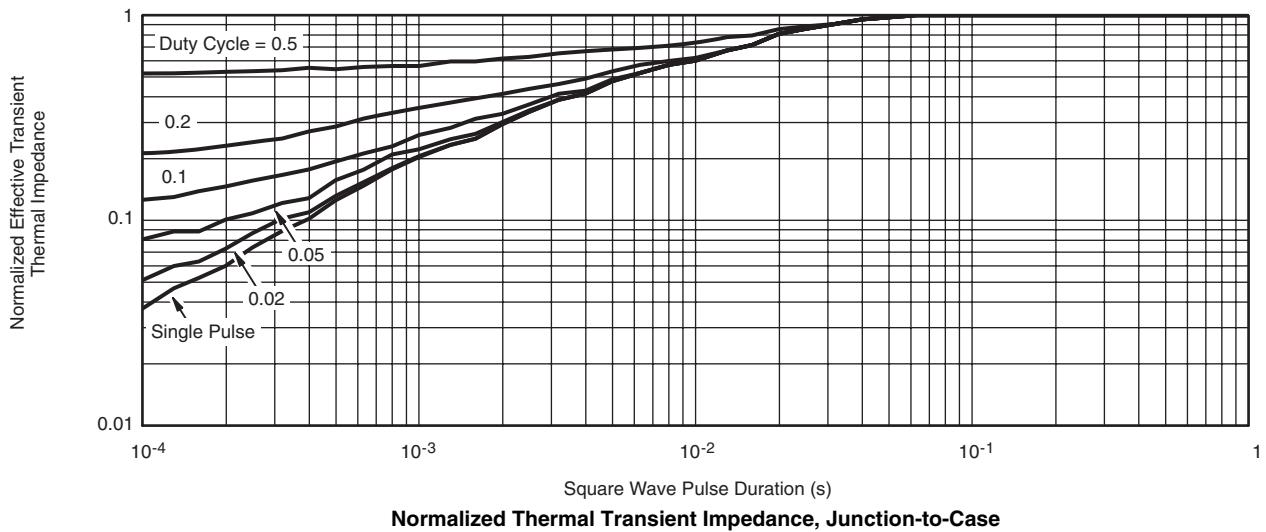
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted**Source-Drain Diode Forward Voltage****On-Resistance vs. Gate-to-Source Voltage****Threshold Voltage****Single Pulse Power (Junction-to-Ambient)*** $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified**Safe Operating Area, Junction-to-Ambient**

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


* The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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